TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VHC299F,TC74VHC299FT

8-Bit Pipo Shift Register with Asynchronous Clear

The TC74VHC299 is an advanced high speed CMOS 8-BIT PIPO SHIFT REGISTER fabricated with silicon gate C^2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

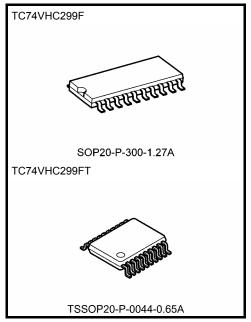
It has a four modes (HOLD, SHIFT LEFT, SHIFT RIGHT and LOAD DATA) controlled by the two selection inputs (S0, S1).

When one or both enable ($\overline{G}1$, $\overline{G}2$) are high, the eight I/O are forced to the high-impedance state; however, sequential operation or clearing of the register is not affected.

All inputs are equipped with protection circuits against static discharge.

Features (Note 1) (Note 2) (Note 3)

- High speed: $f_{max} = 160 \text{ MHz}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 4 \mu A \text{ (max)}$ at $T_a = 25 \text{°C}$
- High noise immunity: V_{NIH} = V_{NIL} = 28% V_{CC} (min)
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: $V_{CC (opr)} = 2 \text{ to } 5.5 \text{ V}$
- Low noise: $V_{OLP} = 1.4 \text{ V (max)}$
- Pin and function compatible with 74ALS299

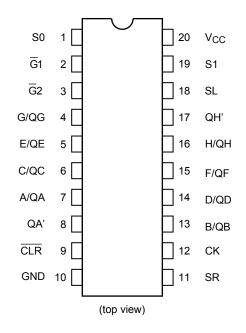


Weight

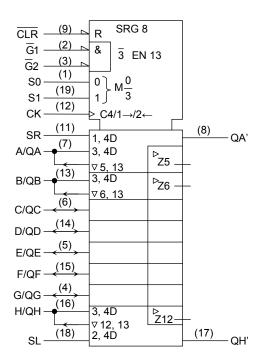
SOP20-P-300-1.27A : 0.22 g (typ.) TSSOP20-P-0044-0.65A : 0.08 g (typ.)

- Note 1: Do not apply a signal to A/QA to H/QH bus terminal when it is in the output mode. Damage may result.
- Note 2: All floating (high impedance) A/QA to H/QH bus terminals must have their input levels fixed by means of pull up or pull down resistors.
- Note 3: A parasitic diode is formed between A/QA to H/QH bus and V_{CC} terminals. Therefore bus terminal can not be used to interface 5 V to 3 V systems directly.

Pin Assignment



IEC Logic Symbol



Truth Table

		Inputs								Inputs /Outputs		puts
Mode	Function Select		Output Control		OK	Se		A /O A		0.41	0.11	
	CLR	S1	S0	G1 (Note)	G2 (Note)	CK	SL	SR	A/QA	H/QH	L L L	QH'
Z	L	Н	Н	Х	Х	Х	Х	Х	Z	Z	L	L
Clear	L	L	Х	L	L	Х	Х	Х	L	L	L	L
Clear	L	Х	L	L	L	Х	Х	Х	L	L	L	L
Hold	Н	L	L	L	L	Х	Х	Х	QA ₀	QH ₀	QA ₀	QH ₀
Shift Right	Н	L	Н	L	L		Х	Н	Н	QGn	Н	QGn
Shirt Right	Н	L	Н	L	L		Х	L	L	QGn	L	QGn
Shift Left	Н	Н	L	L	L		Н	Х	QB _n	Н	QB _n	Н
Snitt Lett	Н	Н	L	L	L		L	Х	QB _n	L	QB _n	L
Load	Н	Н	Н	Х	Х		Х	Х	а	h	а	h

Note: When one or both output controls are high, the eight input/output terminals are in the high-impedance state; however sequential or clearing of the register is not affected.

Z: High impedance

Q_{n0}: The level of Q_n before the indicated steady-state input conditions were established.

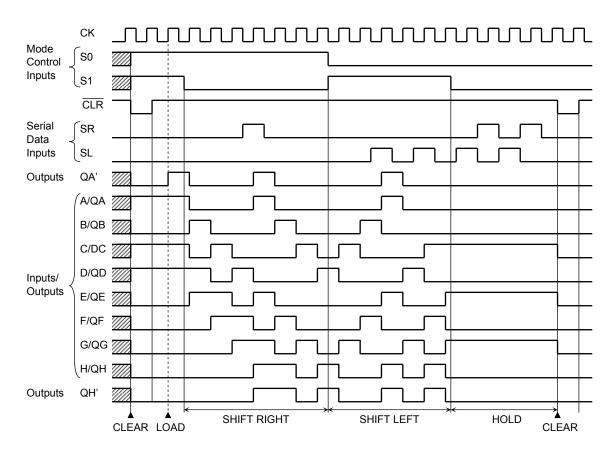
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 $Q_{nn}\!\!:$ The level of Q_n before the most recent active transition indicated by \downarrow or $\uparrow.$

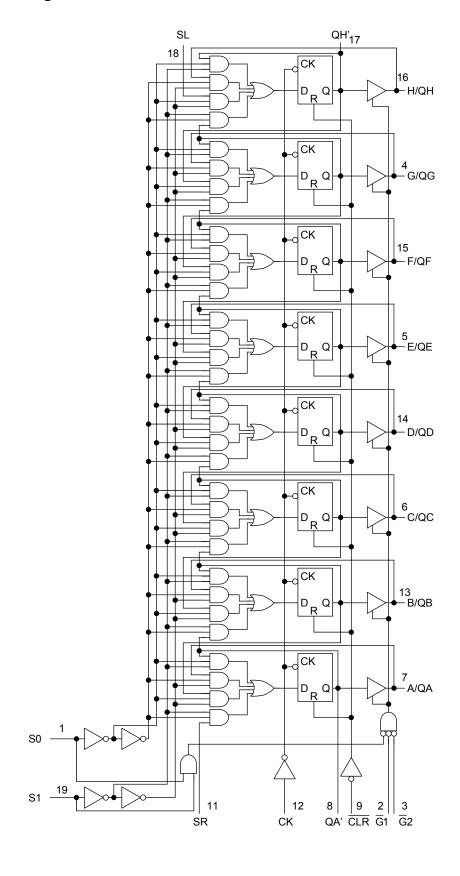
a, h: The level of the steady-state inputs A, H, respectively.

X: Don't care.

Timing Chart



System Diagram





Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	−0.5 to 7.0	V
DC input voltage	V _{IN}	−0.5 to 7.0	V
DC bus I/O voltage (A/QA to H/QH')	V _{IN/OUT}	-0.5 to V _{CC} + 0.5	V
DC output voltage (QA' to QH')	V _{OUT}	-0.5 to V _{CC} + 0.5	V
Input diode current	lικ	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±80	mA
Power dissipation	P _D	180	mW
Storage temperature	T _{stg}	−65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2.0 to 5.5	V
Input voltage	V _{IN}	0 to 5.5	V
DC bus I/O voltage (A/QA to H/QH)	V _{IN/OUT}	0 to V _{CC}	V
DC output voltage (QA' to QH')	V _{OUT}	0 to V _{CC}	V
Operating temperature	T _{opr}	−40 to 85	°C
Input rise and fall time	dt/dV	0 to 100 (V _{CC} = 3.3 ± 0.3 V) 0 to 20 (V _{CC} = 5 ± 0.5 V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.



Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition			7	Γa = 25°(a = o 85°C	Unit
	•			V _{CC} (V)	Min	Тур.	Max	Min	Max	
High-level input				2.0	1.50	_	_	1.50	_	
voltage	V_{IH}	_		3.0 to 5.5	V _{CC} × 0.7	_	_	V _{CC} × 0.7	_	V
Low-level input				2.0	_	_	0.50	_	0.50	
voltage	V _{IL}		_	3.0 to 5.5	_	_	V _{CC} × 0.3	_	V _{CC} × 0.3	V
				2.0	1.9	2.0	_	1.9	_	
	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA	3.0	2.9	3.0	_	2.9	_	
High-level output voltage				4.5	4.4	4.5	_	4.4	_	V
			I _{OH} = -4 mA	3.0	2.58	_	_	2.48	_	
			I _{OH} = -8 mA	4.5	3.94	_	_	3.80	_	
	V _{OL}	V _{IN} = V _{IH} or V _{IL}		2.0	_	0.0	0.1	_	0.1	V 4
			I _{OL} = 50 μA	3.0	_	0.0	0.1	_	0.1	
Low-level output voltage				4.5	_	0.0	0.1	_	0.1	
			I _{OL} = 4 mA	3.0	_	_	0.36	_	0.44	
			I _{OL} = 8 mA	4.5	_	-	0.36	1	0.44	
3-state output	loz	V _{IN} = V _{IH} or	V _{IL}	5.5	_		±0.25	-	±2.50	μΑ
off-state current		V _{OUT} = V _{CC} or GND								ľ
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	1	±0.1	1	±1.0	μΑ
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or	r GND	5.5			4.0		40.0	μΑ



AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Те	st Condition		-	Ta = 25°0			a = o 85°C	Unit
Characteriotics	,		V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	
	t _{pLH}		00.00	15	_	12.2	17.2	1.0	19.8	
Propagation delay time			3.3 ± 0.3	50	_	14.7	20.7	1.0	23.3	no
(CK-QA', QH')	t _{pHL}	_	5.0 ± 0.5	15	_	8.5	10.8	1.0	12.0	ns
			5.0 ± 0.5	50	_	10.0	12.8	1.0	14.0	
			3.3 ± 0.3	15	_	13.0	19.0	1.0	22.0	
Propagation delay time	+		3.3 ± 0.3	50	_	15.5	22.5	1.0	25.5	no
(CLR -QA', QH')	t _{pHL}	_	50.05	15	_	9.1	11.2	1.0	13.5	ns
			5.0 ± 0.5	50	_	10.8	13.2	1.0	15.5	
			3.3 ± 0.3	15	_	10.3	14.3	1.0	16.6	
Propagation delay time	t _{pLH}		3.3 ± 0.3	50	_	12.8	17.8	1.0	20.1	
(CK-QA to QH)	t _{pHL}	_	5.0 ± 0.5	15	_	7.3	9.1	1.0	10.4	ns
			5.0 ± 0.5	50	_	8.8	11.1	1.0	12.4	
	t _{pHL}		3.3 ± 0.3	15	_	10.8	17.0	1.0	19.5	- ns
Propagation delay time		_	3.3 ± 0.3	50	_	13.3	20.5	1.0	23.0	
(CLR -QA to QH)			5.0 ± 0.5	15	_	7.7	10.5	1.0	12.0	
,				50	_	9.2	12.5	1.0	14.0	
	^t pZL ^t pZH		3.3 ± 0.3	15	_	13.3	16.5	1.0	19.2	
Output enable time		R _L = 1 kΩ	3.3 ± 0.3	50	_	14.8	19.0	1.0	21.7	ns
Output enable time			5.0 ± 0.5	15	_	8.9	9.7	1.0	11.3	
				50	_	10.4	11.2	1.0	12.6	
Output disable time	t _{pLZ}	$R_L = 1 k\Omega$	3.3 ± 0.3	50	_	18.0	21.3	1.0	24.3	ns
Output disable time	t _{pHZ}	IVE - 1 K22	5.0 ± 0.5	50	_	11.8	13.2	1.0	15.0	115
			3.3 ± 0.3	15	65	100	_	55	_	
Maximum clock	f		3.3 ± 0.3	50	55	90	_	50	_	MHz
frequency	f _{max}		5.0 ± 0.5	15	125	160	_	110	_	IVII IZ
			3.0 ± 0.3	50	115	150	_	100	_	
Input capacitance	C _{IN}		_		_	4	10	_	_	pF
Bus I/O capacitance (A/QA to H/QH)	C _{OUT}		_		_	8	_	_	_	pF
Power dissipation capacitance	C _{PD}			(Note)	_	110	_	_	_	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$



Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$)

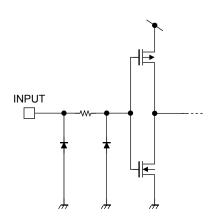
Characteristics	Symbol	Test Condition	Test Condition			Ta = -40 to 85°C	Unit
			V _{CC} (V)	Тур.	Limit	Limit	
Minimum pulse width	t _{w (H)}		3.3 ± 0.3	_	7.0	8.0	ns
(CK)	t _{w (L)}	_	5.0 ± 0.5	_	7.0	8.0	115
Minimum pulse width	.		3.3 ± 0.3	_	6.0	7.0	20
(CLR)	t _{w (L)}	_	5.0 ± 0.5	_	6.0	7.0	ns
Minimum set-up time	4		3.3 ± 0.3	_	8.5	10.0	20
(SL, SR)	t _s	_	5.0 ± 0.5	-	5.0	5.0	ns
Minimum set-up time	4		3.3 ± 0.3	_	8.0	9.0	ns
(A to H)	t _s	_	5.0 ± 0.5	-	4.0	4.0	115
Minimum set-up time	4		3.3 ± 0.3	_	14.5	17.0	ns
(S0, S1)	t _s	_	5.0 ± 0.5	-	7.0	8.0	113
Minimum hold time	4.		3.3 ± 0.3	_	1.0	1.0	ns
(SL, SR)	t _h	_	5.0 ± 0.5	-	1.0	1.0	115
Minimum hold time	4.		3.3 ± 0.3	_	0.5	0.5	ns
(A to H)	t _h	_	5.0 ± 0.5	-	1.5	1.5	115
Minimum hold time	4.		3.3 ± 0.3	_	0	0	ns
(S0, S1)	t _h		5.0 ± 0.5		0.5	0.5	115
Minimum removal time			3.3 ± 0.3	_	5.0	6.0	20
(CLR)	t _{rem}		5.0 ± 0.5	_	4.0	4.0	ns

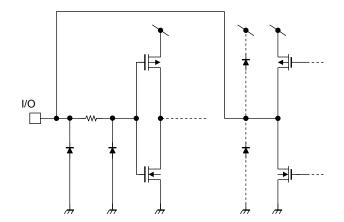
Noise Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition			Ta = 25°C		
Characteristics	Symbol		V _{CC} (V)	Тур.	Limit	Unit	
Quiet output maximum dynamic	V	C _I = 50 pF	5.0	0.9	1.2	V	
V _{OL}	V_{OLP}	CL = 30 μr	5.0	0.9	1.2	V	
Quiet output minimum dynamic	V _{OLV}	C ₁ = 50 pF	5.0	-0.9	-1.2	V	
V _{OL}	VOLV	ОС – 30 рі	5.0	0.9	1.2	V	
Minimum high level dynamic input Voltage	V_{IHD}	C _L = 50 pF	5.0	_	3.5	V	
Maximum low high level dynamic input Voltage	V _{ILD}	C _L = 50 pF	5.0		1.5	V	

Input Equivalent Circuit

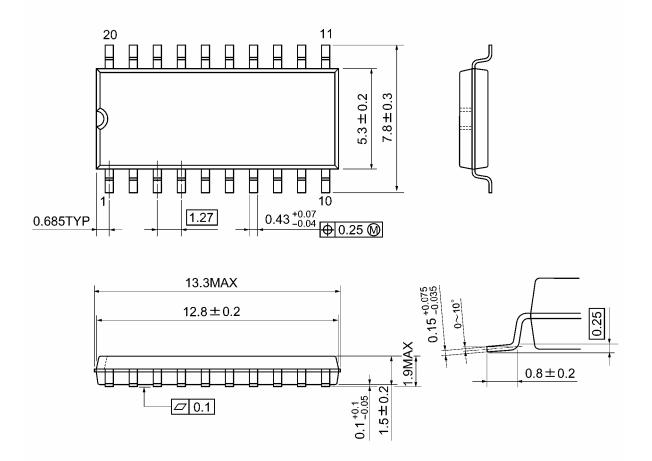
A/QA to H/QH Bus Terminal Equivalent Circuit





Package Dimensions

SOP20-P-300-1.27A Unit: mm



Weight: 0.22 g (typ.)

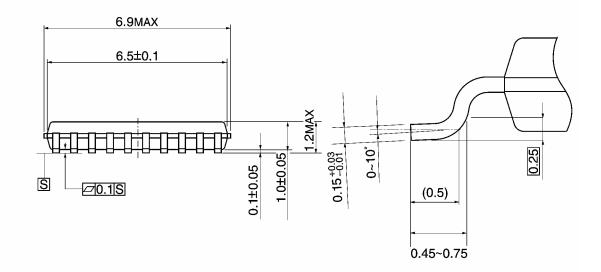
Package Dimensions

TSSOP20-P-0044-0.65A

Unit: mm

 $0.22\substack{+0.09 \\ -0.06}$

0.65



| |0.13M

Weight: 0.08 g (typ.)

0.325TYP

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20070701-EN GENERAL

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